PTO-1449 (Modified)

SERIAL NUMBER

09/865,528

Sheet 1 of 3

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

APPLICANT(S) Yamada

ATTY. DOCKET NO.

219.003-US

FILING DATE

GROUP ART UNIT 2829

May 29, 2001

U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
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VN	63-009807	1/1988	Japan			
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EXAMINER

DATE CONSIDERED

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Sheet 1 of 3 ATTY. DOCKET NO. SERIAL NUMBER PTO-1449 (Modified) 219.003-US 09/865,528 U.S. DEPARTMENT OF COMMERCE APPLICANT(S) PATENT AND TRADEMARK OFFICE Yamada FILING DATE GROUP ART UNIT INFORMATION DISCLOSURE STATEMENT May 29, 2001 BY APPLICANT 2829 U.S. PATENT DOCUMENTS EXAMINER DOCUMENT DATE NAME SUB FILING INITIALS NUMBER CLASS CLASS DATE VN 5,989,919 11/1999 Aoki VN 10/2002 Karpol et al. 6,466,315 FOREIGN PATENT DOCUMENTS SUB examiner DOCUMENT CLASS CLASS COUNTRY NUMBER DATE INITIALS OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) EXAMINER DATE CONSIDERED

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